

UNITED STATES PATENT AND TRADEMARK OFFICE

Examiner: To Be Assigned

Art Unit: To Be Assigned

Re: Application of:

Volker SEYFRIED

Serial No.:

To Be Assigned

Filed:

Herewith

For:

**METHOD FOR MICROSCOPY, AND
MICROSCOPE**

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

June 23, 2003

S i r:

In accordance with the provisions of 37 C.F.R. § 1.97, Applicant hereby makes of record the documents listed on the accompanying PTO-1449 Form (1 page) for consideration by the Examiner in connection with the examination of the above-identified patent application. While the references are being submitted herewith, some or all of the references may not constitute prior art under the U.S. patent laws.

This Information Disclosure Statement is filed under 37 C.F.R. §1.97 (b), before the mailing date of a First Office Action, therefore no fee is believed due.

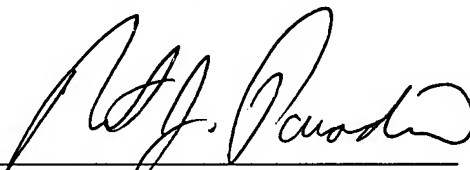
In the event any additional fee is due in connection with this response or if any fee has been overpaid, the deficiency or overpayment should be charged to our Deposit Account No. 50-

0552.

It is respectfully requested that the references cited in the accompanying PTO-1449 form be considered and made of record. It is respectfully submitted that the pending claims are patentable over all of the references made of record at this time.

Respectfully submitted,

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By: 

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LIST OF PRIOR ART CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT(S): Volker SEYFRIED

FILING DATE: Herewith

GROUP: To Be Assigned

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER							DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
	AA	5	7	3	1	5	8	8	Mar. 24, 1998	Hell et al.	250	458.1	
	AB	5	7	7	7	7	3	2	Jul. 7, 1998	Hanninen et al.	356	318	
	AC	5	0	3	4	6	1	3	Jul. 23, 1991	Denk et al.	250	458.1	
	AD												
	AF												
	AF												
	AG												
	AH												
	AI												

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
													YES	NO
	AJ	9	5	2	1	3	9	3	Aug. 10, 1995	WIPO			see US '588	
	AK	4	4	1	4	9	4	0	Nov. 2, 1995	DE - Germany			see US '732	
	AJ	0	0	0	4	3	5	2	Jan. 27, 2000	WIPO			in English	
	AK													
	AF													
	AM													
	AN													
	AO													
	AF													

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR	
	AS	
	AT	

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.